



STB8NA50

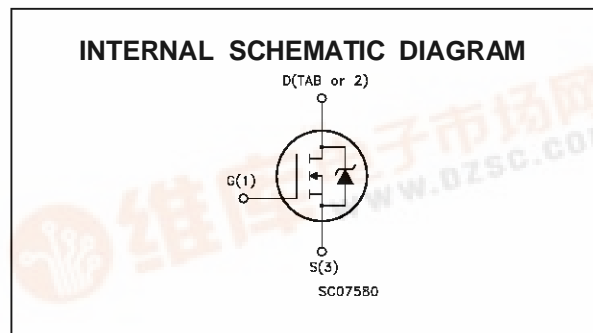
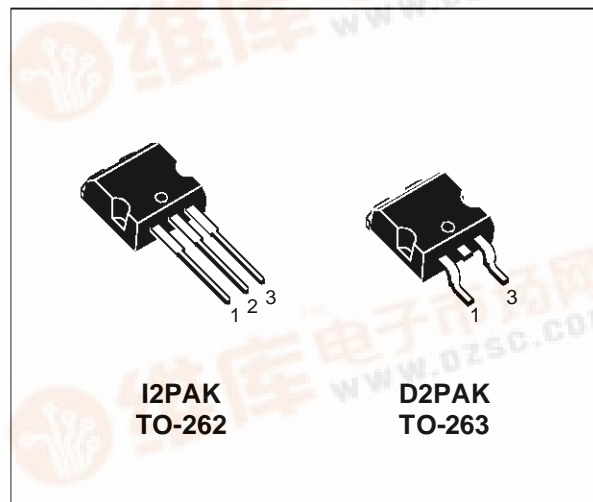
N - CHANNEL ENHANCEMENT MODE FAST POWER MOS TRANSISTOR

| TYPE | V _{DSS} | R _{DS(on)} | I _D |
|----------|------------------|---------------------|----------------|
| STB8NA50 | 500 V | < 0.85 Ω | 8 A |

- TYPICAL R_{DS(on)} = 0.7 Ω
- ± 30V GATE TO SOURCE VOLTAGE RATING
- 100% AVALANCHE TESTED
- REPETITIVE AVALANCHE DATA AT 100°C
- LOW INTRINSIC CAPACITANCES
- GATE CHARGE MINIMIZED
- REDUCED THRESHOLD VOLTAGE SPREAD
- THROUGH-HOLE I2PAK (TO-262) POWER PACKAGE IN TUBE (SUFFIX "-1")
- SURFACE-MOUNTING D2PACK (TO-263) POWER PACKAGE IN TUBE (NO SUFFIX) OR IN TAPE & REEL (SUFFIX "T4")

APPLICATIONS

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITCH MODE POWER SUPPLIES (SMPS)
- DC-AC CONVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLIES AND MOTOR DRIVE



ABSOLUTE MAXIMUM RATINGS

| Symbol | Parameter | Value | Unit |
|---------------------|---|------------|------|
| V _{DS} | Drain-source Voltage (V _{GS} = 0) | 500 | V |
| V _{DGR} | Drain- gate Voltage (R _{GS} = 20 kΩ) | 500 | V |
| V _{GS} | Gate-source Voltage | ± 30 | V |
| I _D | Drain Current (continuous) at T _c = 25 °C | 8 | A |
| I _D | Drain Current (continuous) at T _c = 100 °C | 5.3 | A |
| I _{DM} (●) | Drain Current (pulsed) | 32 | A |
| P _{tot} | Total Dissipation at T _c = 25 °C | 125 | W |
| | Derating Factor | 1 | W/°C |
| T _{stg} | Storage Temperature | -65 to 150 | °C |
| T _j | Max. Operating Junction Temperature | 150 | °C |

(●) Pulse width limited by safe operating area



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THERMAL DATA

| | | | | |
|-----------------------|--|-----|------|------|
| R _{thj-case} | Thermal Resistance Junction-case | Max | 1 | °C/W |
| R _{thj-amb} | Thermal Resistance Junction-ambient | Max | 62.5 | °C/W |
| R _{thc-sink} | Thermal Resistance Case-sink | Typ | 0.5 | °C/W |
| T _j | Maximum Lead Temperature For Soldering Purpose | | 300 | °C |

AVALANCHE CHARACTERISTICS

| Symbol | Parameter | Max Value | Unit |
|-----------------|---|-----------|------|
| I _{AR} | Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T _j max, δ < 1%) | 8 | A |
| E _{AS} | Single Pulse Avalanche Energy (starting T _j = 25 °C, I _D = I _{AR} , V _{DD} = 50 V) | 350 | mJ |
| E _{AR} | Repetitive Avalanche Energy (pulse width limited by T _j max, δ < 1%) | 11 | mJ |
| I _{AR} | Avalanche Current, Repetitive or Not-Repetitive (T _c = 100 °C, pulse width limited by T _j max, δ < 1%) | 5.3 | A |

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|----------------------|---|--|------|------|-------------|----------|
| V _{(BR)DSS} | Drain-source Breakdown Voltage | I _D = 250 μA V _{GS} = 0 | 500 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current (V _{GS} = 0) | V _{DS} = Max Rating V _{DS} = Max Rating x 0.8 T _c = 125 °C | | | 250 1000 | μA μA |
| I _{GSS} | Gate-body Leakage Current (V _{DS} = 0) | V _{GS} = ± 30 V | | | ± 100 | nA |

ON (*)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|---------------------|-----------------------------------|---|------|------|-------------|--------|
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} = V _{GS} I _D = 250 μA | 2.25 | 3 | 3.75 | V |
| R _{DS(on)} | Static Drain-source On Resistance | V _{GS} = 10V I _D = 4 A V _{GS} = 10V I _D = 4 A T _c = 100°C | | 0.7 | 0.85 1.7 | Ω Ω |
| I _{D(on)} | On State Drain Current | V _{DS} > I _{D(on)} x R _{DS(on)max} V _{GS} = 10 V | 8 | | | A |

DYNAMIC

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|---------------------|------------------------------|--|------|------|------|------|
| g _{fs} (*) | Forward Transconductance | V _{DS} > I _{D(on)} x R _{DS(on)max} I _D = 4 A | 4.5 | 6.5 | | S |
| C _{iss} | Input Capacitance | V _{DS} = 25 V f = 1 MHz V _{GS} = 0 | | 1200 | 1600 | pF |
| C _{oss} | Output Capacitance | | | 190 | 250 | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 55 | 75 | pF |

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|----------------|-----------------------|---|------|------|------|------------|
| $t_{d(on)}$ | Turn-on Time | $V_{DD} = 250\text{ V}$ $I_D = 4\text{ A}$ | | 18 | 25 | ns |
| t_r | Rise Time | $R_G = 4.7\ \Omega$ $V_{GS} = 10\text{ V}$ (see test circuit, figure 3) | | 25 | 35 | ns |
| $(di/dt)_{on}$ | Turn-on Current Slope | $V_{DD} = 400\text{ V}$ $I_D = 8\text{ A}$ $R_G = 47\ \Omega$ $V_{GS} = 10\text{ V}$ (see test circuit, figure 5) | | 220 | | A/ μ s |
| Q_g | Total Gate Charge | $V_{DD} = 400\text{ V}$ $I_D = 8\text{ A}$ $V_{GS} = 10\text{ V}$ | | 55 | 75 | nC |
| Q_{gs} | Gate-Source Charge | | | 9 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 25 | | nC |

SWITCHING OFF

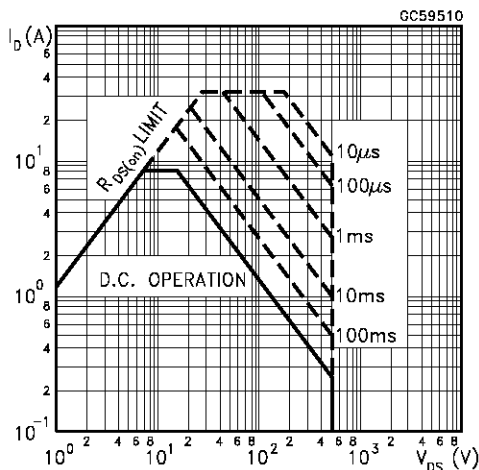
| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|---------------|-----------------------|--|------|------|------|------|
| $t_{r(Voff)}$ | Off-voltage Rise Time | $V_{DD} = 400\text{ V}$ $I_D = 8\text{ A}$ | | 15 | 22 | ns |
| t_f | Fall Time | $R_G = 4.7\ \Omega$ $V_{GS} = 10\text{ V}$ | | 15 | 22 | ns |
| t_c | Cross-over Time | (see test circuit, figure 5) | | 25 | 35 | ns |

SOURCE DRAIN DIODE

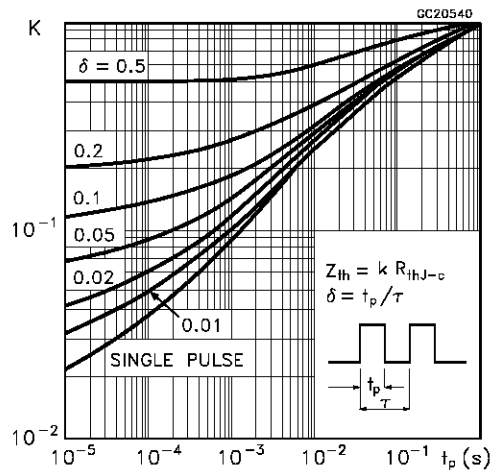
| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|--------------------|-------------------------------|---|------|------|------|---------------|
| I_{SD} | Source-drain Current | | | | 8 | A |
| $I_{SDM}(\bullet)$ | Source-drain Current (pulsed) | | | | 32 | A |
| $V_{SD} (*)$ | Forward On Voltage | $I_{SD} = 8\text{ A}$ $V_{GS} = 0$ | | | 1.6 | V |
| t_{rr} | Reverse Recovery Time | $I_{SD} = 8\text{ A}$ $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 100\text{ V}$ $T_j = 150\text{ }^\circ\text{C}$ (see test circuit, figure 5) | | 500 | | ns |
| Q_{rr} | Reverse Recovery Charge | | | 6.5 | | μC |
| I_{RRM} | Reverse Recovery Current | | | 26 | | A |

(*) Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %
 (•) Pulse width limited by safe operating area

Safe Operating Area

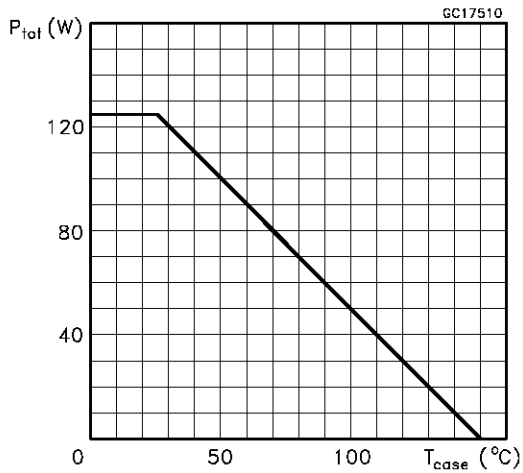


Thermal Impedance

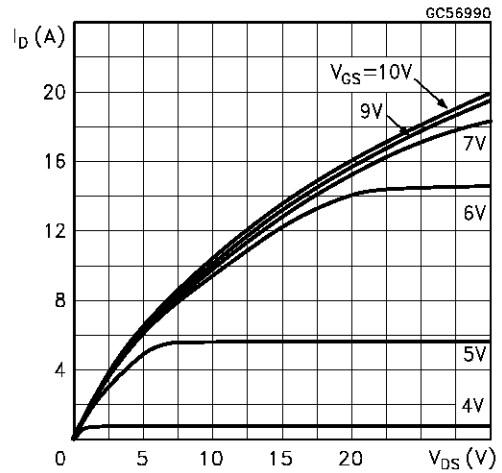


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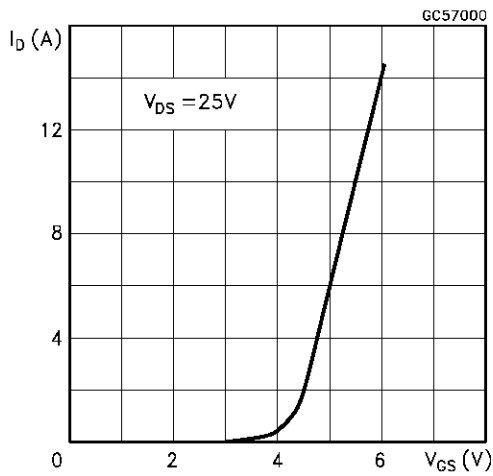
Derating Curve



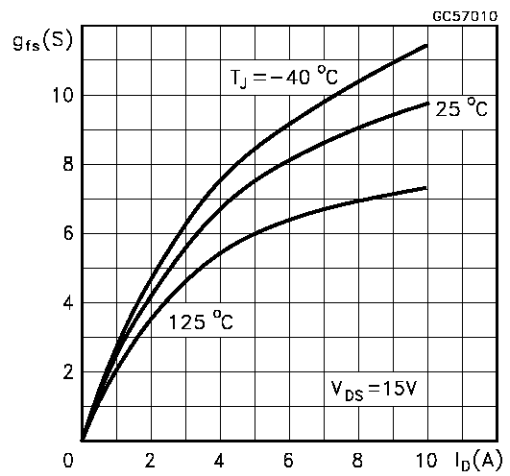
Output Characteristics



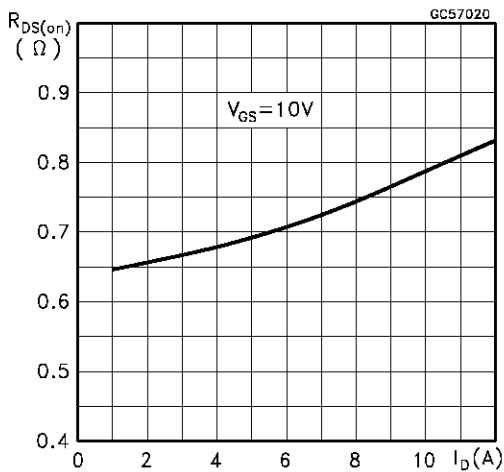
Transfer Characteristics



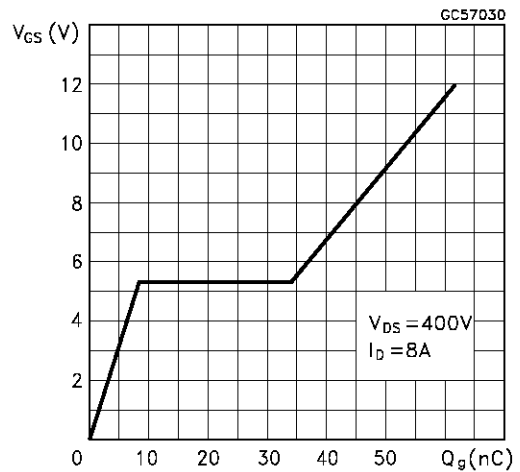
Transconductance



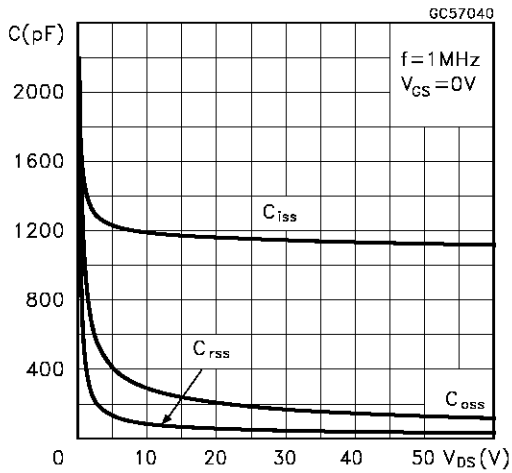
Static Drain-source On Resistance



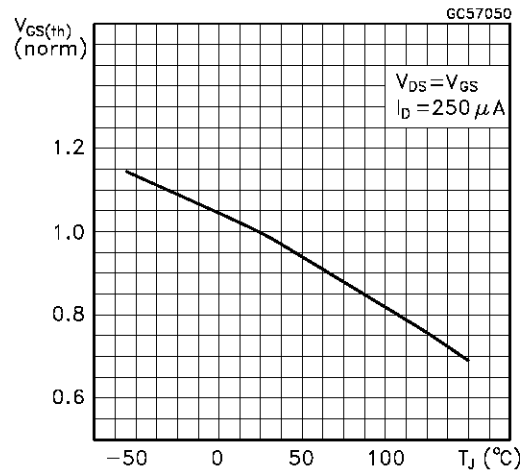
Gate Charge vs Gate-source Voltage



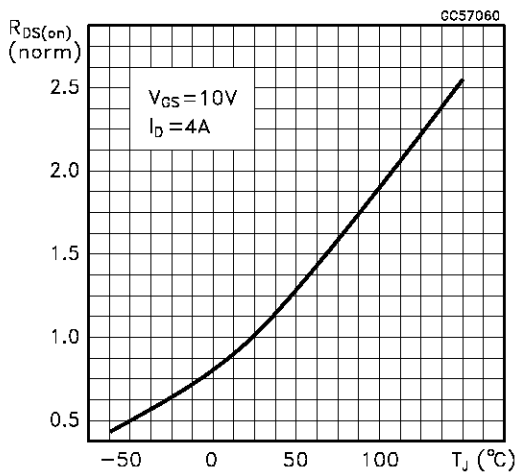
Capacitance Variations



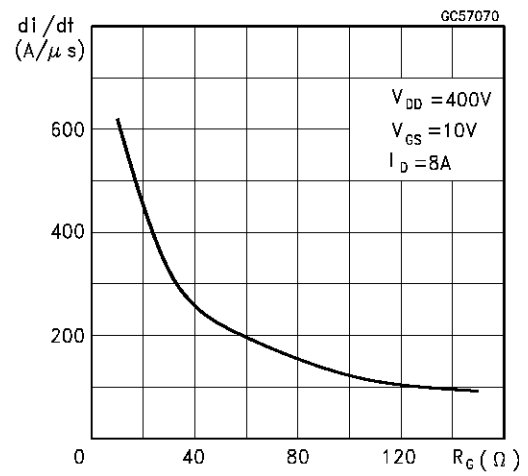
Normalized Gate Threshold Voltage vs Temperature



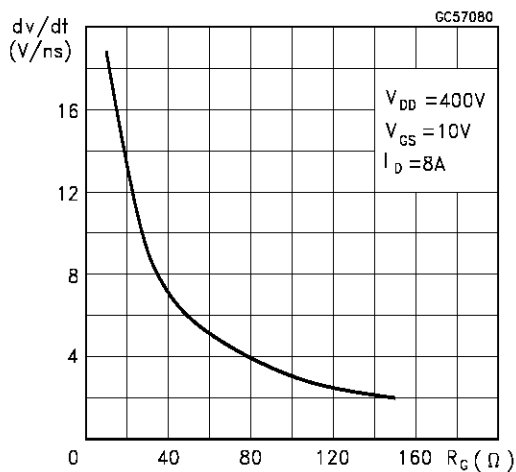
Normalized On Resistance vs Temperature



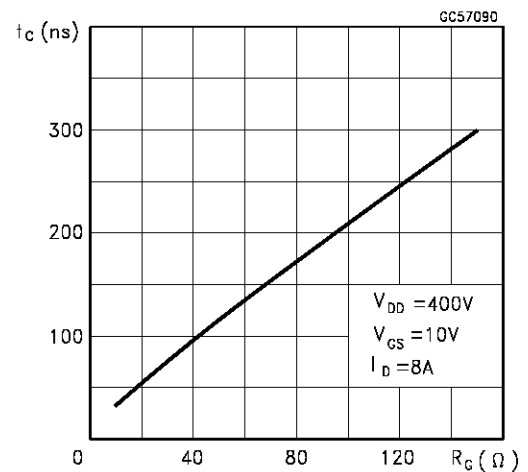
Turn-on Current Slope



Turn-off Drain-source Voltage Slope

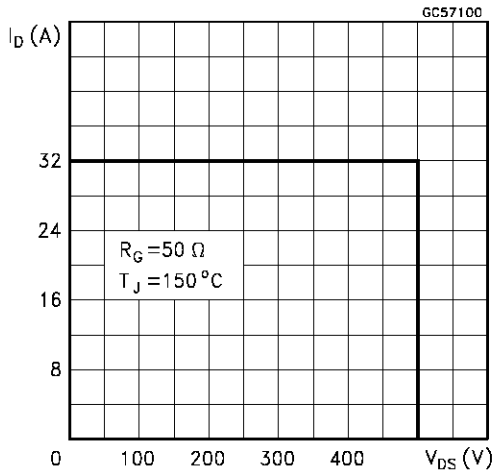


Cross-over Time

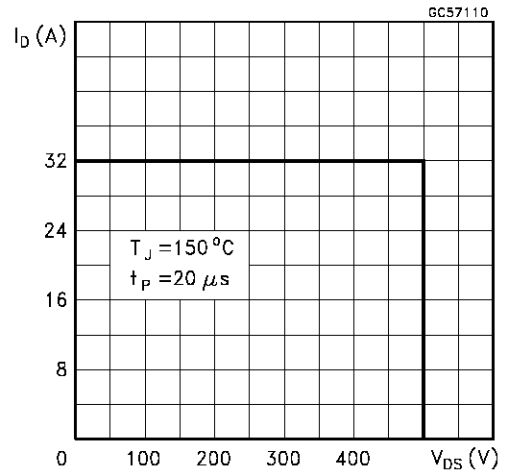


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Switching Safe Operating Area



Accidental Overload Area



Source-drain Diode Forward Characteristics

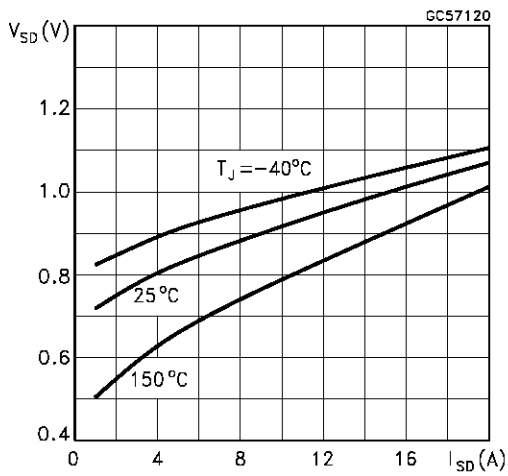


Fig. 1: Unclamped Inductive Load Test Circuit

Fig. 2: Unclamped Inductive Waveform

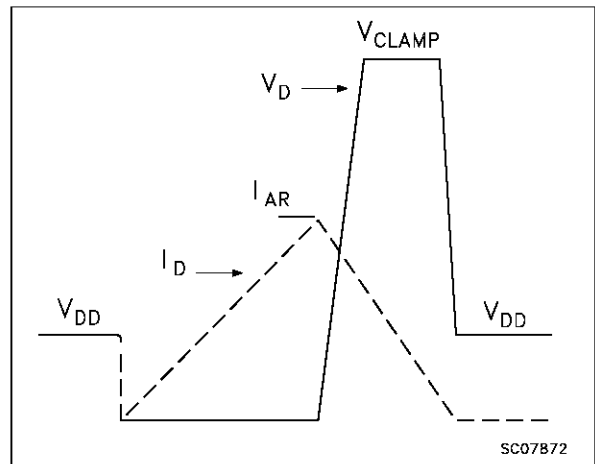
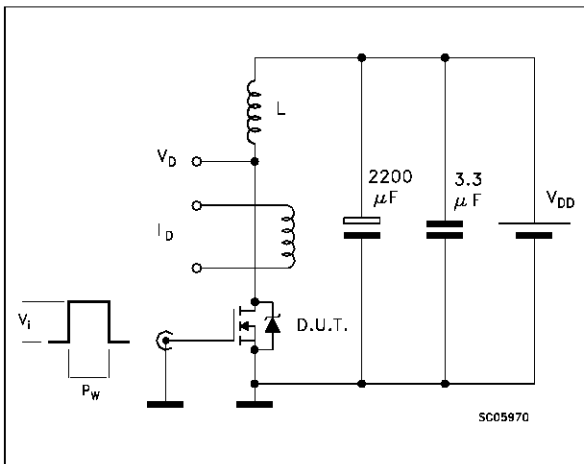


Fig. 3: Switching Times Test Circuits For Resistive Load

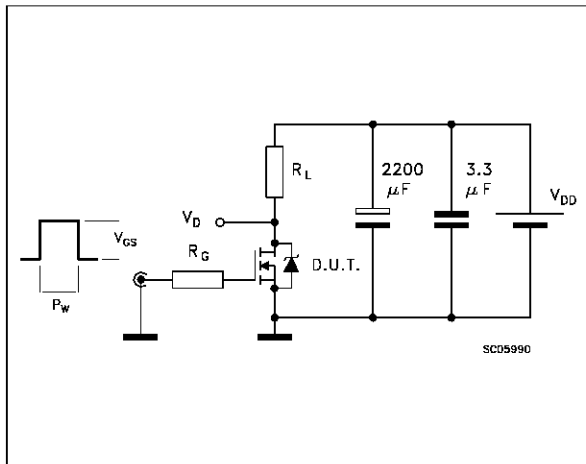


Fig. 4: Gate Charge test Circuit

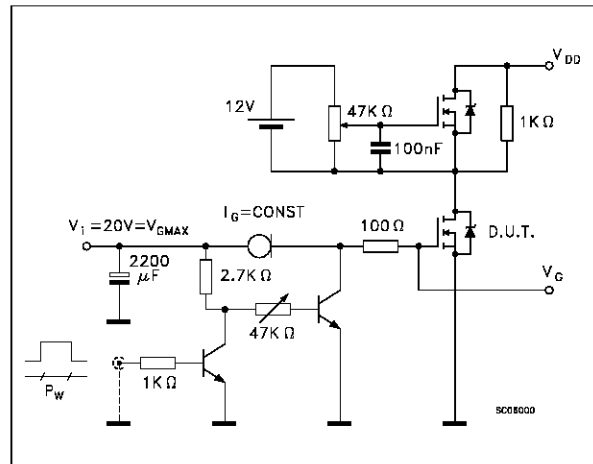
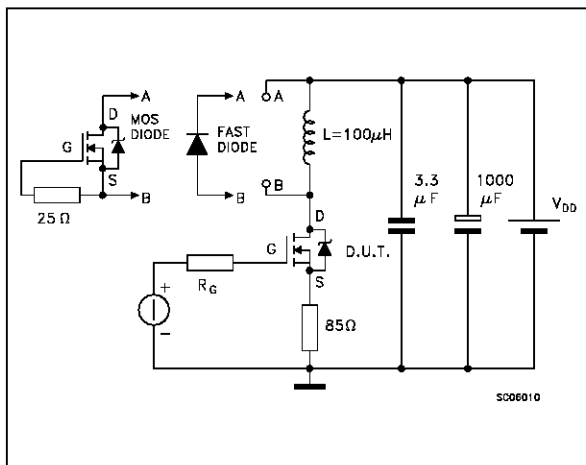
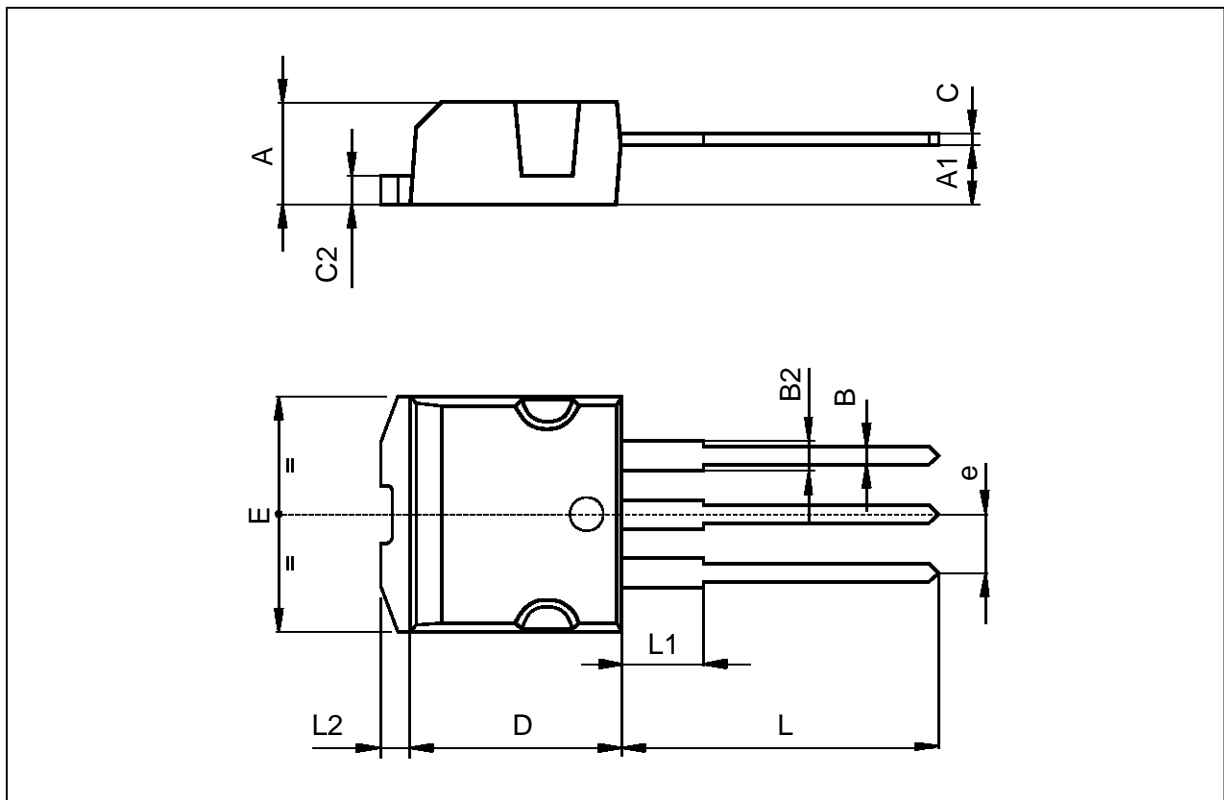


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times



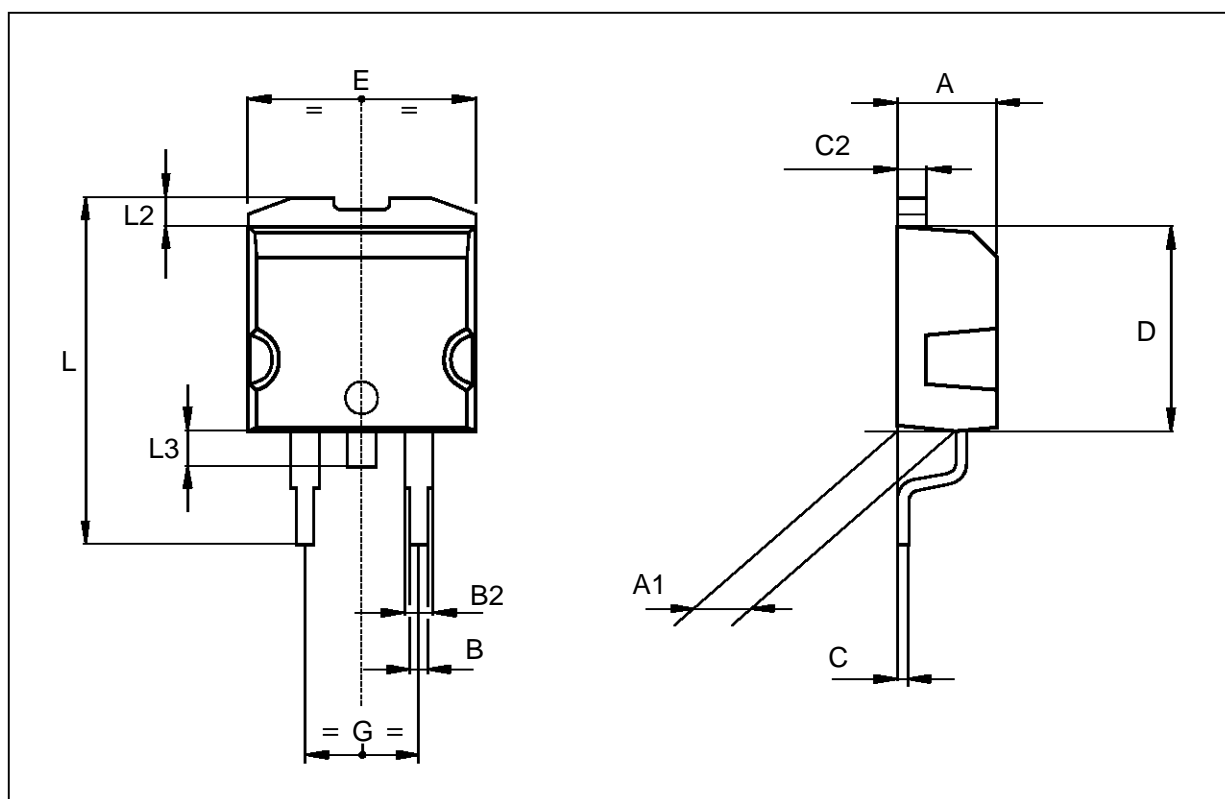
TO-262 (I2PAK) MECHANICAL DATA

| DIM. | mm | | | inch | | |
|------|------|------|-------|-------|------|-------|
| | MIN. | TYP. | MAX. | MIN. | TYP. | MAX. |
| A | 4.3 | | 4.6 | 0.169 | | 0.181 |
| A1 | 2.49 | | 2.69 | 0.098 | | 0.106 |
| B | 0.7 | | 0.93 | 0.027 | | 0.036 |
| B1 | 1.2 | | 1.38 | 0.047 | | 0.054 |
| B2 | 1.25 | | 1.4 | 0.049 | | 0.055 |
| C | 0.45 | | 0.6 | 0.017 | | 0.023 |
| C2 | 1.21 | | 1.36 | 0.047 | | 0.053 |
| D | 9 | | 9.35 | 0.354 | | 0.368 |
| e | 2.44 | | 2.64 | 0.096 | | 0.104 |
| E | 10 | | 10.28 | 0.393 | | 0.404 |
| L | 13.2 | | 13.5 | 0.519 | | 0.531 |
| L1 | 3.48 | | 3.78 | 0.137 | | 0.149 |
| L2 | 1.27 | | 1.37 | 0.050 | | 0.054 |



TO-263 (D2PAK) MECHANICAL DATA

| DIM. | mm | | | inch | | |
|------|------|------|-------|-------|------|-------|
| | MIN. | TYP. | MAX. | MIN. | TYP. | MAX. |
| A | 4.3 | | 4.6 | 0.169 | | 0.181 |
| A1 | 2.49 | | 2.69 | 0.098 | | 0.106 |
| B | 0.7 | | 0.93 | 0.027 | | 0.036 |
| B2 | 1.25 | | 1.4 | 0.049 | | 0.055 |
| C | 0.45 | | 0.6 | 0.017 | | 0.023 |
| C2 | 1.21 | | 1.36 | 0.047 | | 0.053 |
| D | 9 | | 9.35 | 0.354 | | 0.368 |
| E | 10 | | 10.28 | 0.393 | | 0.404 |
| G | 4.88 | | 5.28 | 0.192 | | 0.208 |
| L | 15 | | 15.85 | 0.590 | | 0.624 |
| L2 | 1.27 | | 1.37 | 0.050 | | 0.054 |
| L3 | 1.4 | | 1.75 | 0.055 | | 0.068 |



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